

## Exams for group S16-402

Wed, 16 Dec	08:30 – 10:05	TEST	Scientific Programs of Modern Times	Shmonin D.V.	ДОТ
Fri, 18 Dec	10:15 – 11:50	TEST	Innovative Approaches to Economics and Management	Medvedeva Y.M.	ДОТ
Tue, 22 Dec	12:45 – 14:20	TEST	Space and Television Systems	Krasnyuk A.A.	ДОТ
Tue, 22 Dec	12:45 – 14:20	TEST	Radio frequency and microwave electronics	Bocharov Y.I.	ДОТ
Tue, 22 Dec	14:30 – 16:05	TEST	Physical Principles of Nanoelectronics	Zebrev G.I.	ДОТ
Tue, 22 Dec	16:15 – 17:50	ATT	Sensors Based on Micro- and Nanotechnologies	Podlepetskiy B.I.	ДОТ
Tue, 22 Dec	16:15 – 17:50	ATT	Electronic Sensors	Sogoyan A.V.	ДОТ
Wed, 23 Dec	11:55 – 13:30	TEST	Life Safety	Orlova K.N.	ДОТ
Wed, 23 Dec	16:15 – 17:50	ATT	Principles of functional and microwave microelectronics	Patrikeev L.N.	ДОТ
Wed, 23 Dec	16:15 – 17:50	ATT	Electronic Systems Design	Boychenko D.V.	ДОТ
Thu, 24 Dec	10:15 – 11:50	TEST	Scientific Research Work	Atkin E.V., Elesin V.V., Ulanova A.V., Chukov G.V., Sogoyan A.V., Nekrasov P.V., Krasnyuk A.A., Kondratenko S.V.	ДОТ
Thu, 24 Dec	11:55 – 13:30	TEST	Elements of Analog-to-Digital Systems (Hybrid Systems)	Chumakov A.I.	ДОТ
Fri, 25 Dec	12:45 – 14:20	ATT	Information and measurement systems in microelectronics	Belyakov V.V.	ДОТ
Sat, 26 Dec	12:45 – 14:20	TEST	Quantum Radiophysics	Larkin A.I.	ДОТ
Sat, 26 Dec	16:15 – 17:50	TEST	Effects of ionizing radiation from outer space on electronics		ДОТ
Sat, 26 Dec	17:55 – 19:30	TEST	Methods for evaluating and improving resistance of electronics to the effects of ionizing radiation from outer space		ДОТ
Mon, 28 Dec	10:15 – 12:40	ATT	Technology and Design of Electronic Equipment	Barbashov V.M.	ДОТ
Mon, 28 Dec	14:30 – 16:05	TEST	Methods of Radiation Research	Yanenko A.V., Skorobogatov P.K.	ДОТ
Mon, 28 Dec	16:15 – 17:50	TEST	Extreme Electronics	Yanenko A.V., Skorobogatov P.K.	ДОТ
Wed, 13 Jan	09:00 – 13:00	EXAM	Technology and Design of Electronic Equipment	Barbashov V.M.	ДОТ
Mon, 18 Jan	09:00 – 13:00	EXAM	Principles of functional and microwave microelectronics	Patrikeev L.N.	ДОТ
Mon, 18 Jan	09:00 – 13:00	EXAM	Electronic Systems Design	Boychenko D.V.	ДОТ
Fri, 22 Jan	09:00 – 13:00	EXAM	Sensors Based on Micro- and Nanotechnologies	Podlepetskiy B.I.	ДОТ
Fri, 22 Jan	09:00 – 13:00	EXAM	Electronic Sensors	Sogoyan A.V.	ДОТ
Tue, 26 Jan	09:00 – 13:00	EXAM	Information and measurement systems in microelectronics	Belyakov V.V.	ДОТ